



Materials Science with secondary particles generated from an extreme light source

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New source of secondary particles:

Ions

Positrons

Muons

Neutrons

Materials modification

Materials analysis

Unknown states or phases of matter



Laser driven particle sources for materials science

Advantages may be:

- Higher intensities
- Higher brilliances
- Easier or cheaper

⇒ New physics?

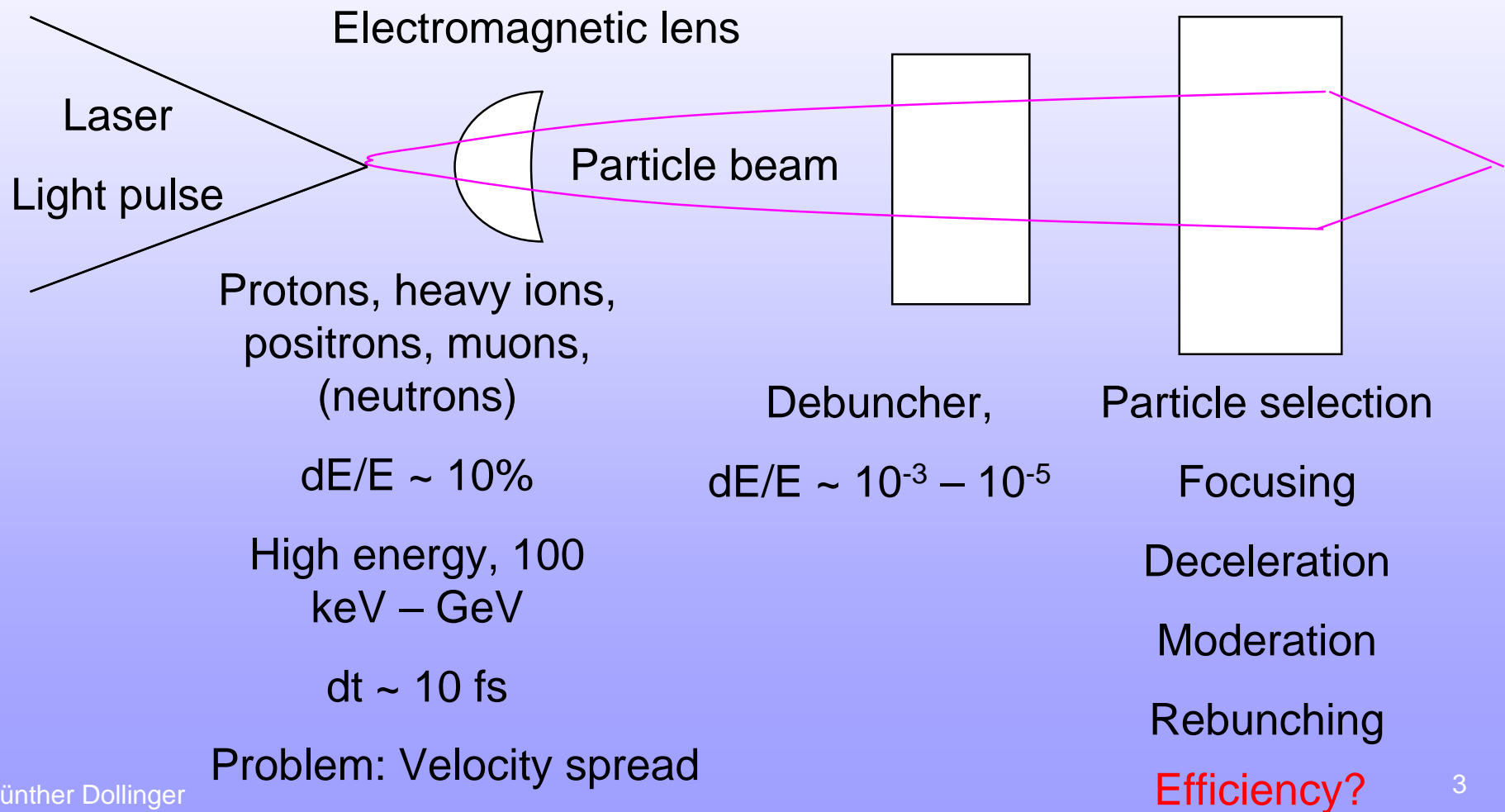
⇒ Easier access?

⇒ New applications?

Necessary: Prove of principle of particle production in comparison to existing facilities



Laser generated secondary particle source for materials science

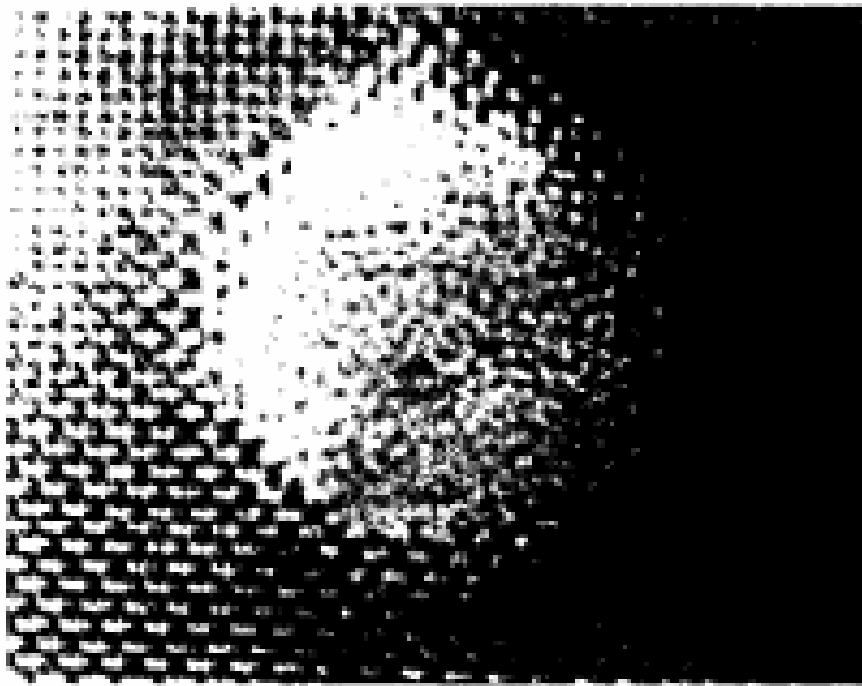




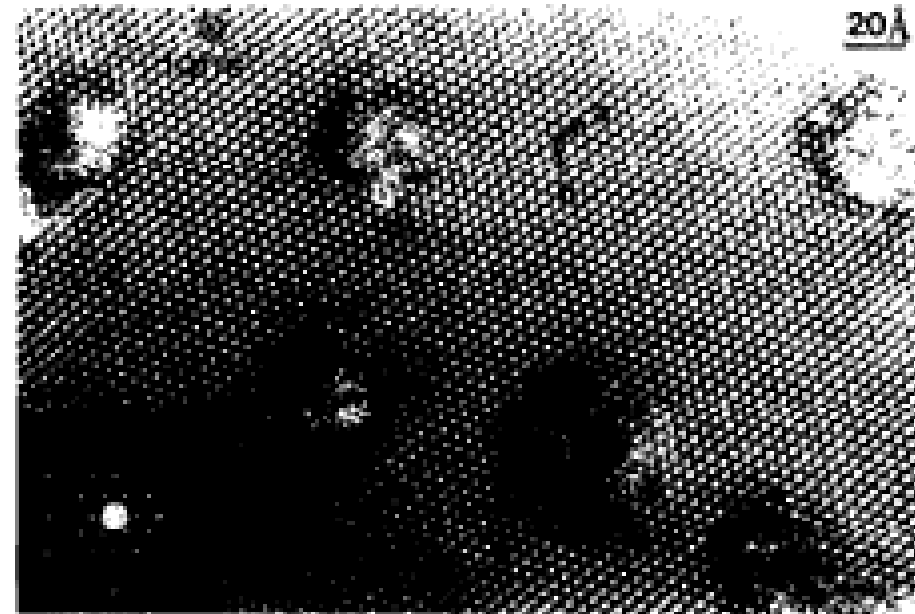
Materials science with laser driven ion beams

- Standard ion beam analysis: no need of Laser driven source
- Materials modification on nanometer scale with secondary particles,
 - i.e. energetic heavy ions (I, Au, U)
(100 MeV – 1 GeV) : replace big accelerators!
 - Nanofocus of high intensity x-rays, electrons, ions?

Latent ion tracks in solids by thermal spike/Coulomb explosion effects



20 Å



ZrO₂

Track diameter about 5 nm, $dE/dx < 20 \text{ keV/nm} \Rightarrow$ nanostructures in insulators

Electron heating within $< \text{fs}$, lattice heating $< 100 \text{ fs}$, cooling within ps

BaFe₁₂O₁₉

F. Studer, M. Hervieu, J.-M. Constantini, M. Toulemonde, Nucl. Instr. and Meth. B 122 (1997) 449

Swift heavy ions from laser pulses

Heavy ion beam (> 100 MeV)

Several ions focused on < 10 nm diameter within ps

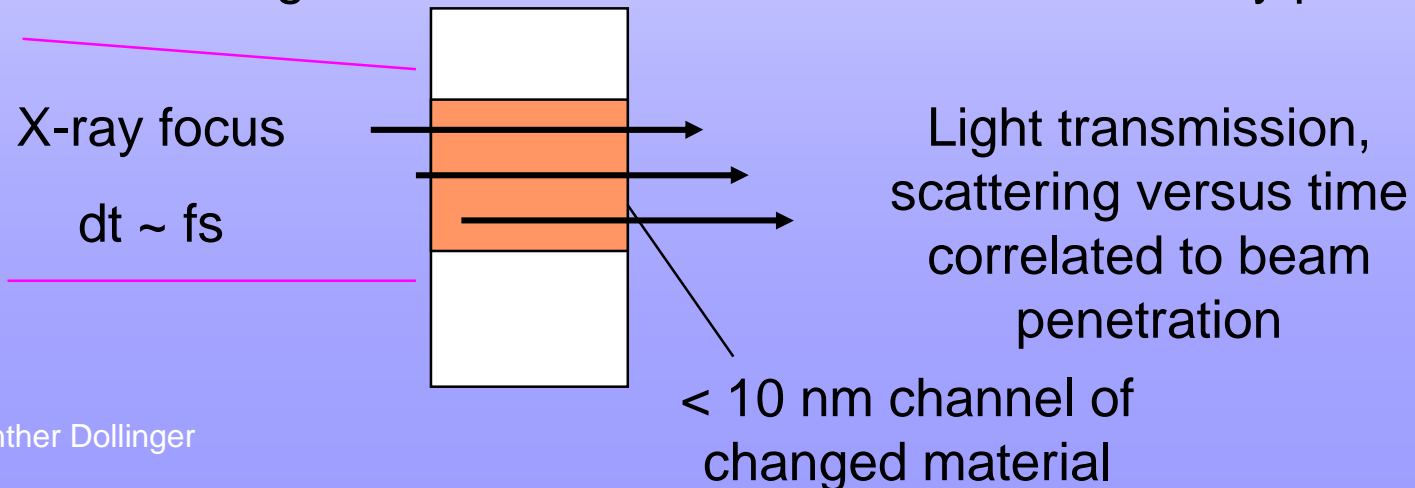
=> latent tracks in metals, simple semiconductors??

=> i.e. nanowires in diamond?

Pump-probe experiments to investigate

Coulomb explosion / thermal spike phenomena

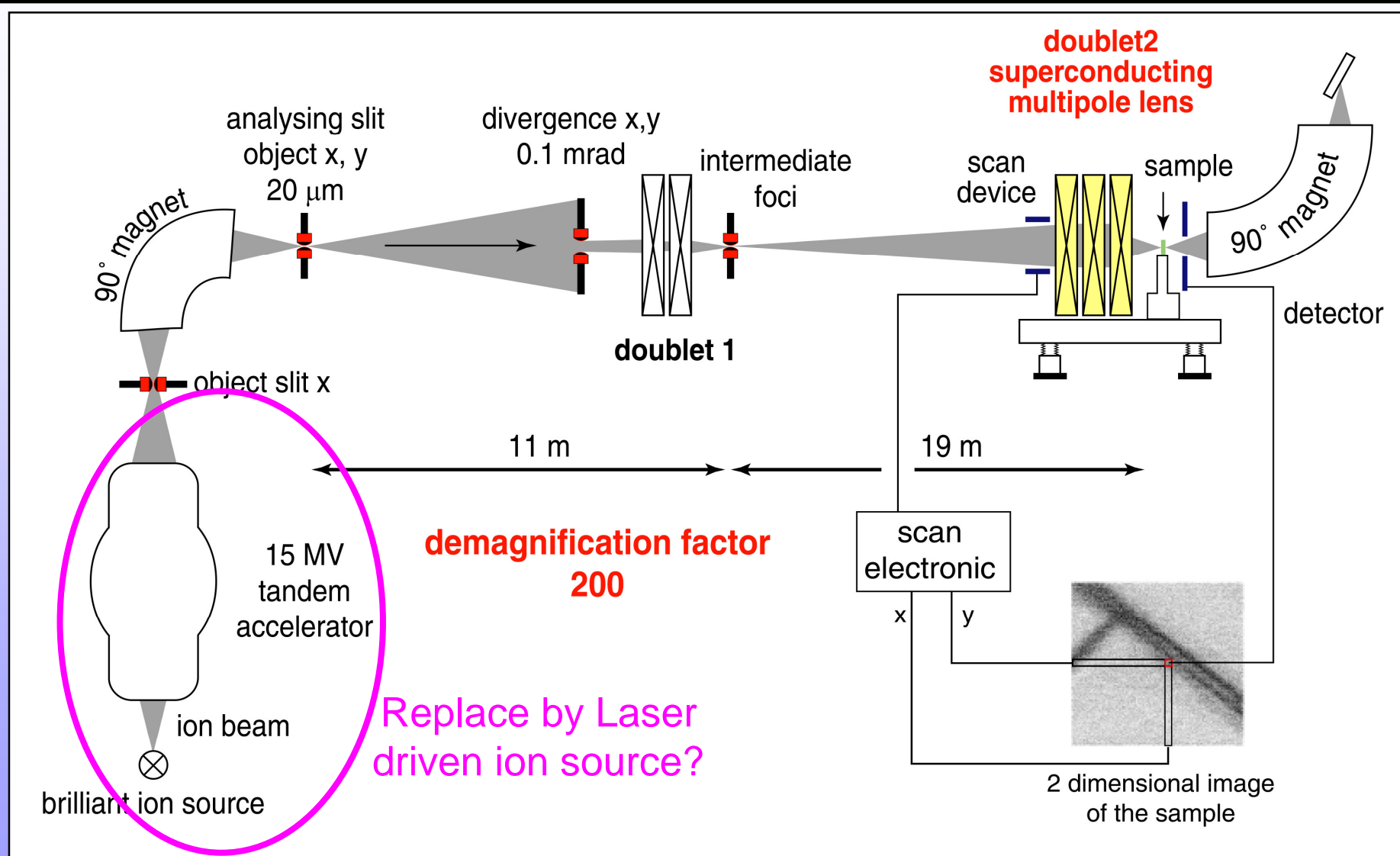
Direct generation of nm-tracks with focused x-ray pulses?



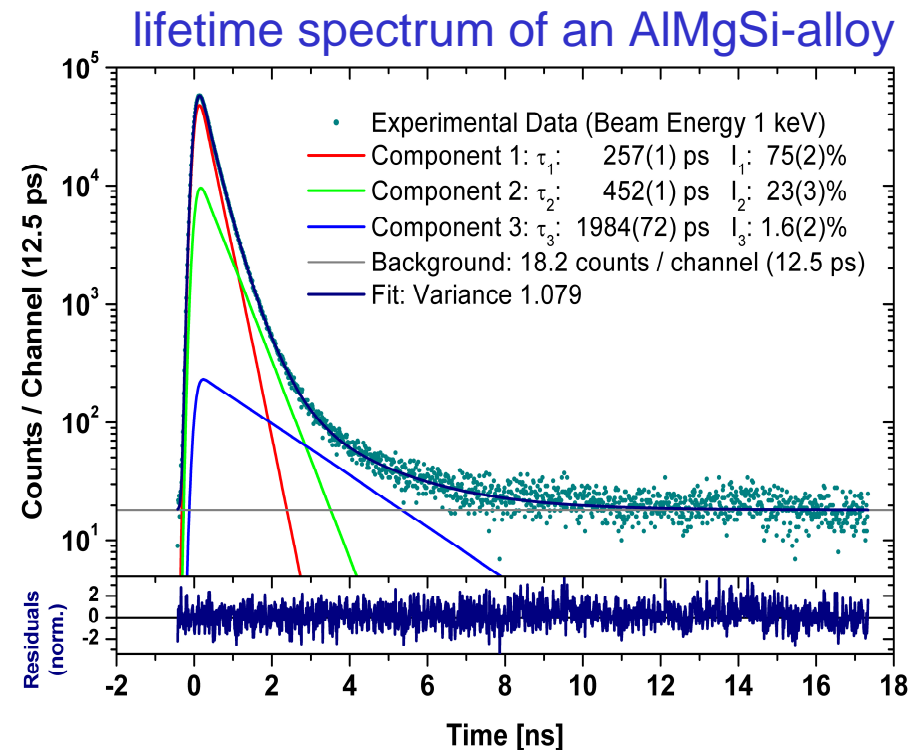
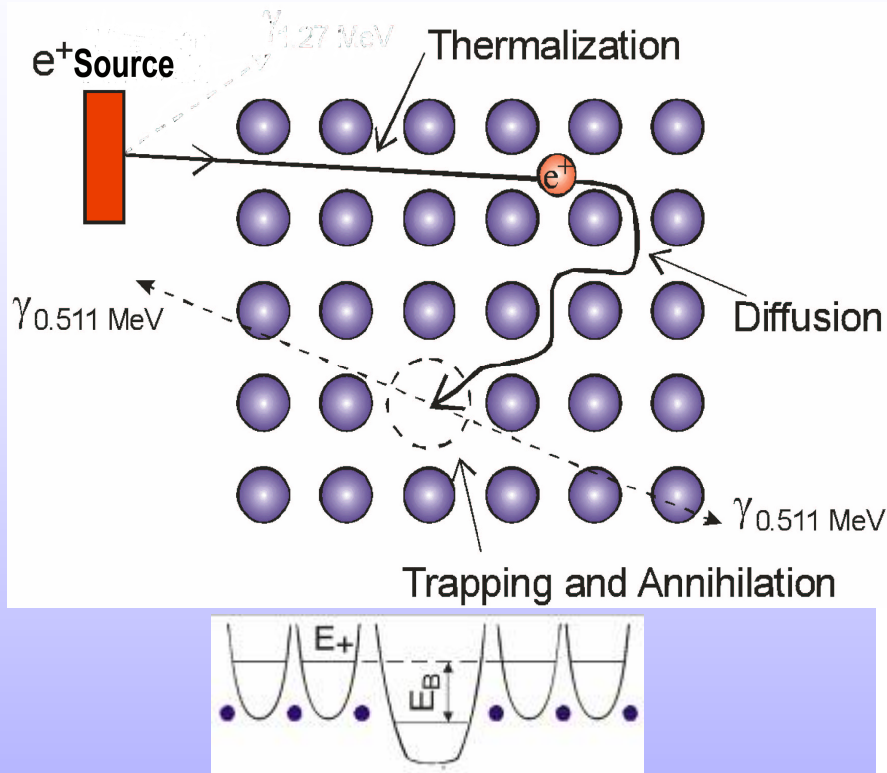


Scheme of SNAKE

Supraleitendes Nanoskop für Angewandte Kernphysikalische Experimente



Positron Annihilation Lifetime Spectroscopy (PALS)



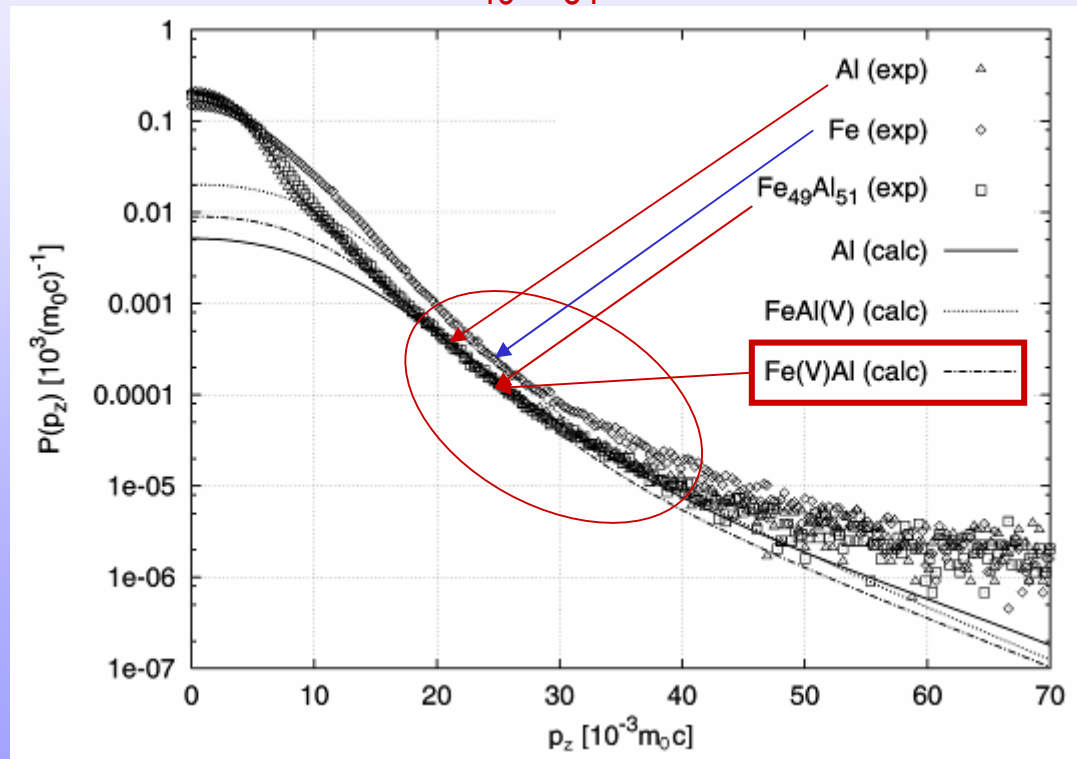
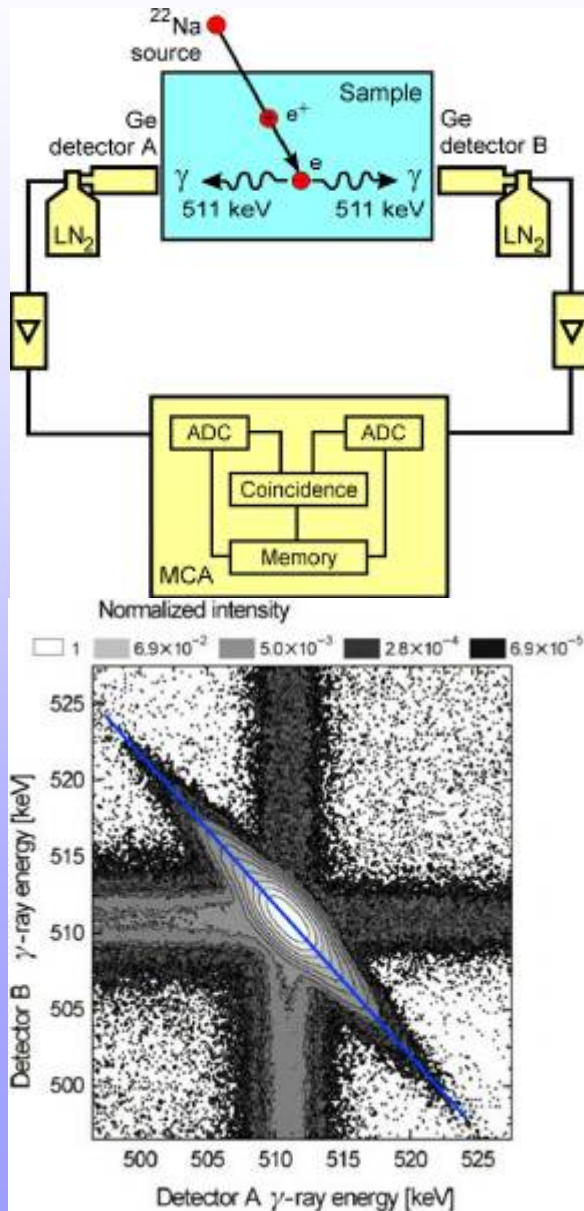
lifetime \propto (local electron density)⁻¹

- defect type from positron lifetime
- defect concentration (\geq at ppm) from intensities

Coincident Spectroscopy of Doppler Broadened Annihilation

=> Momentum distribution of conduction electrons
 => Chemical information

intermetallic $\text{Fe}_{49}\text{Al}_{51}$

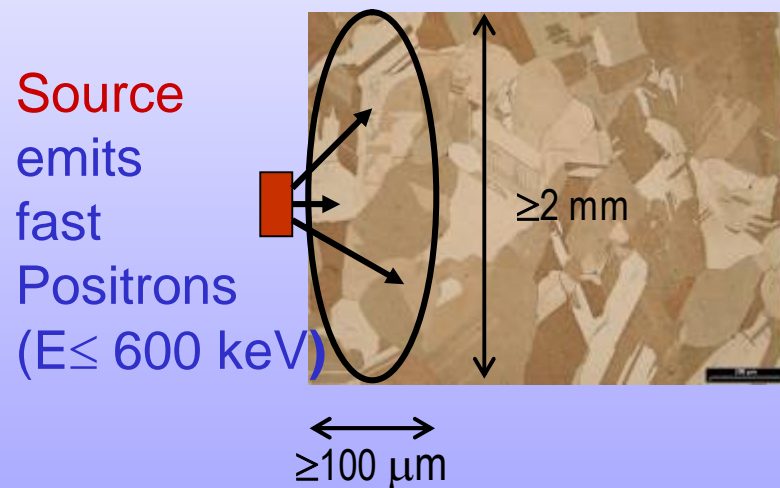


W. Egger, G. Bischof, V. Gröger, G. Krexner
 Materials Science Forum 363-365 (2001) 82-84

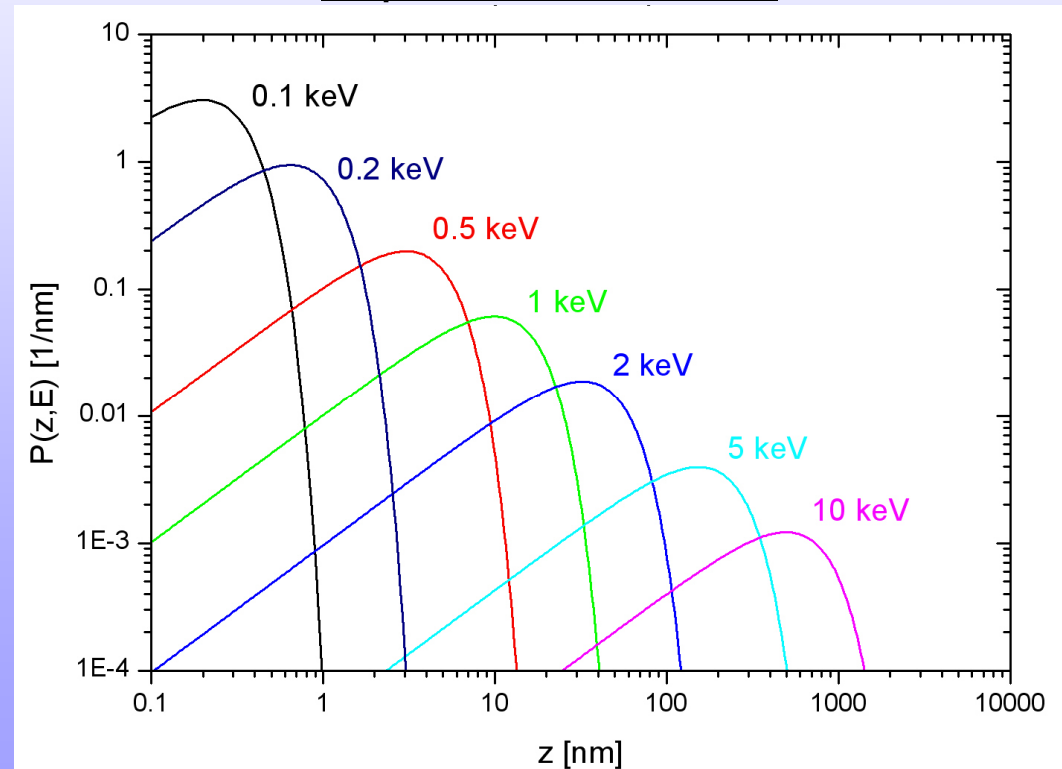
Monoenergetic Positron-Beams: => Depth profile of vacancy type defects

- Conventional method: defect-structure averaged over mm^3
- Problem: grain-boundaries, surfaces, precipitates etc. buried in volume signal
- Solution: monoenergetic positron-beams of variable energy

Conventional Method



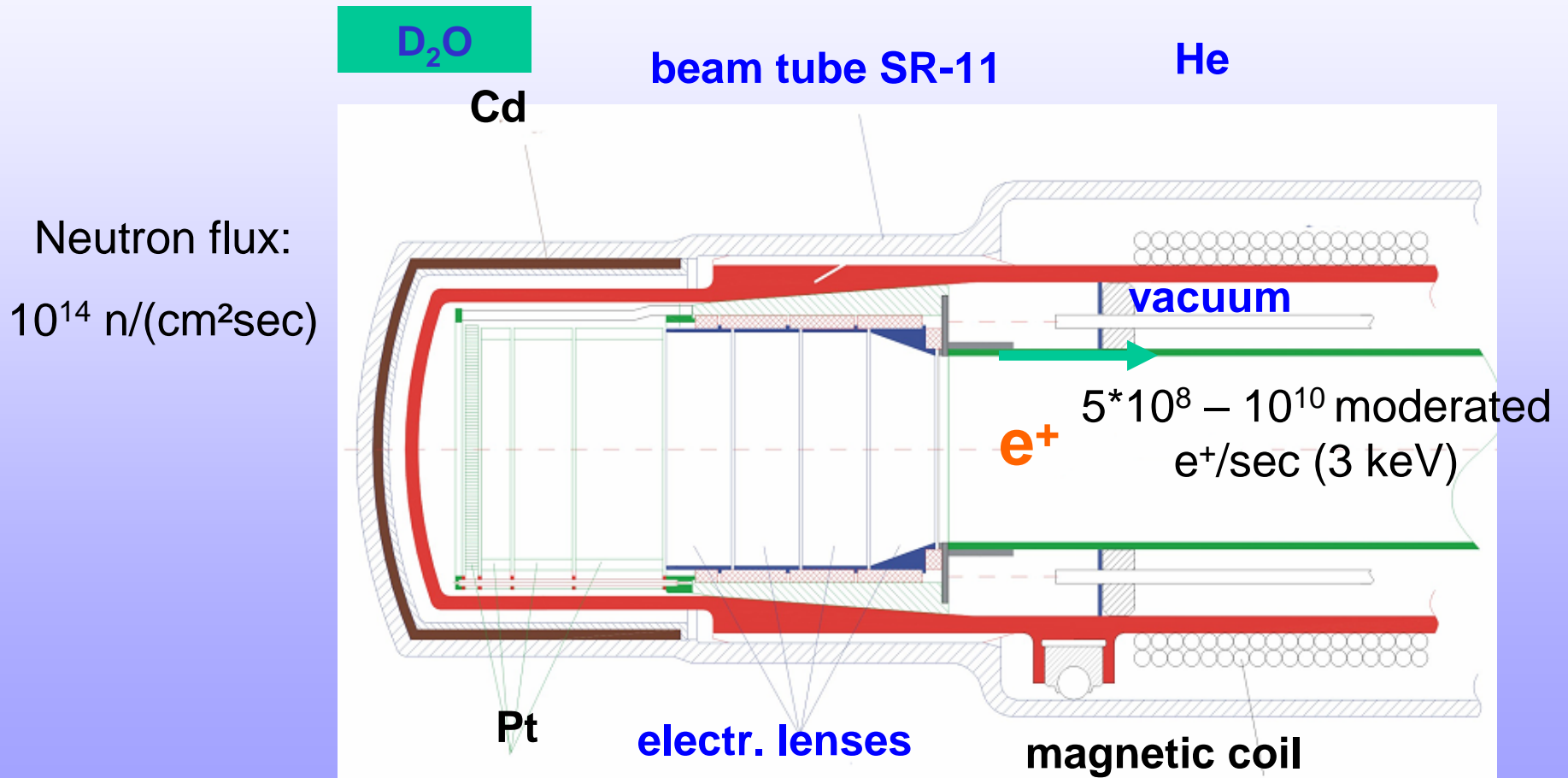
Implantation Profile





Design of the Positron Source NEPOMUC at the FRM-II: Most intense slow positron beam

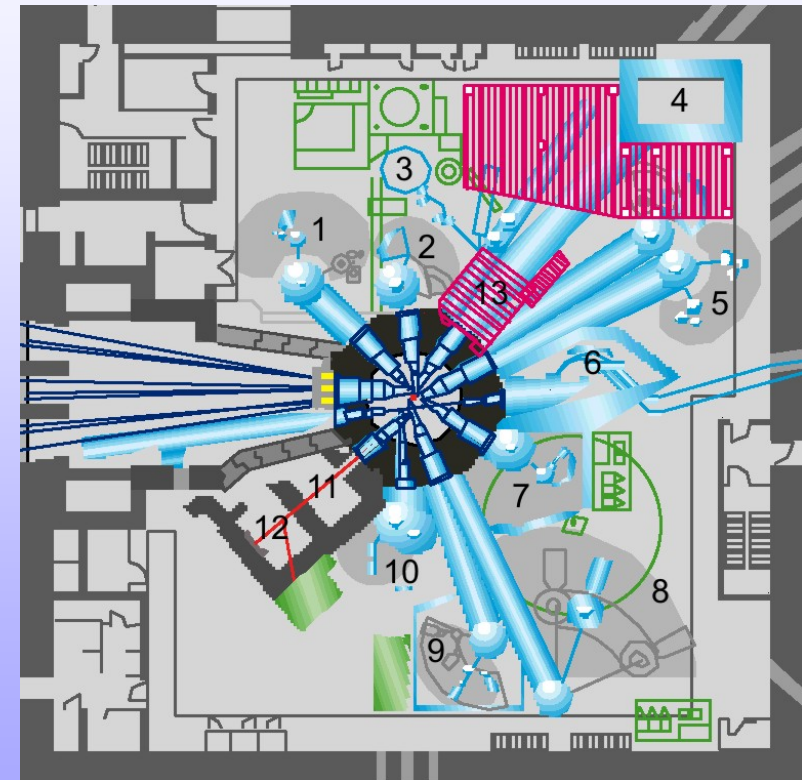
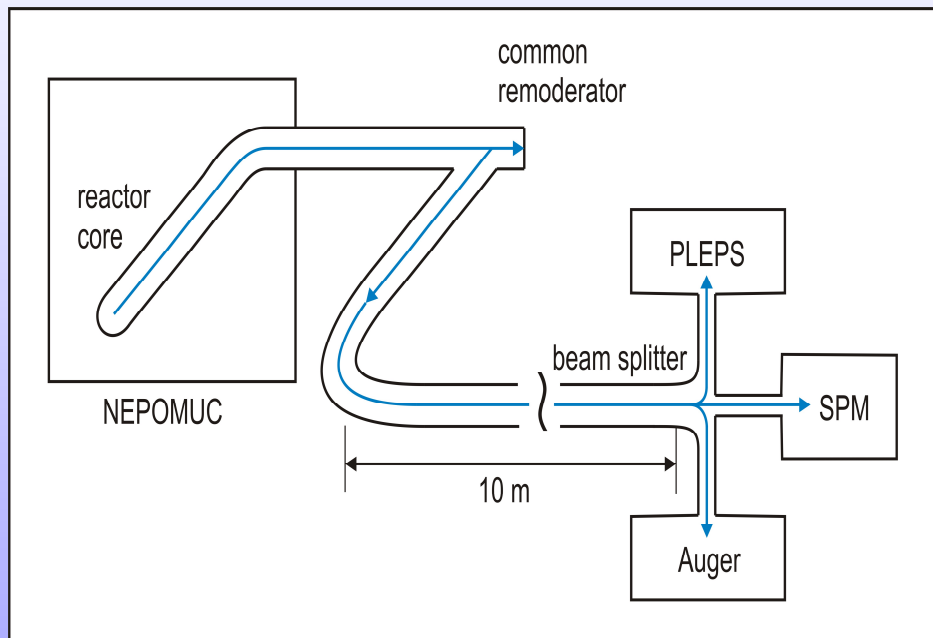
C. Hugenschmidt, K. Schreckenbach, G. Kögel, P. Sperr, W. Triftshäuser Mat. Sci. For. 445-446 (2004)



$4 \cdot 10^{13}$ e⁺/sec in
Pt-structure

Intense positron source (NEPOMUC) at new Munich research reactor FRM II

C. Hugenschmidt, K. Schreckenbach, G. Kögel, P. Sperr, W. Triftshäuser Mat. Sci. For. 445-446 (2004) 480



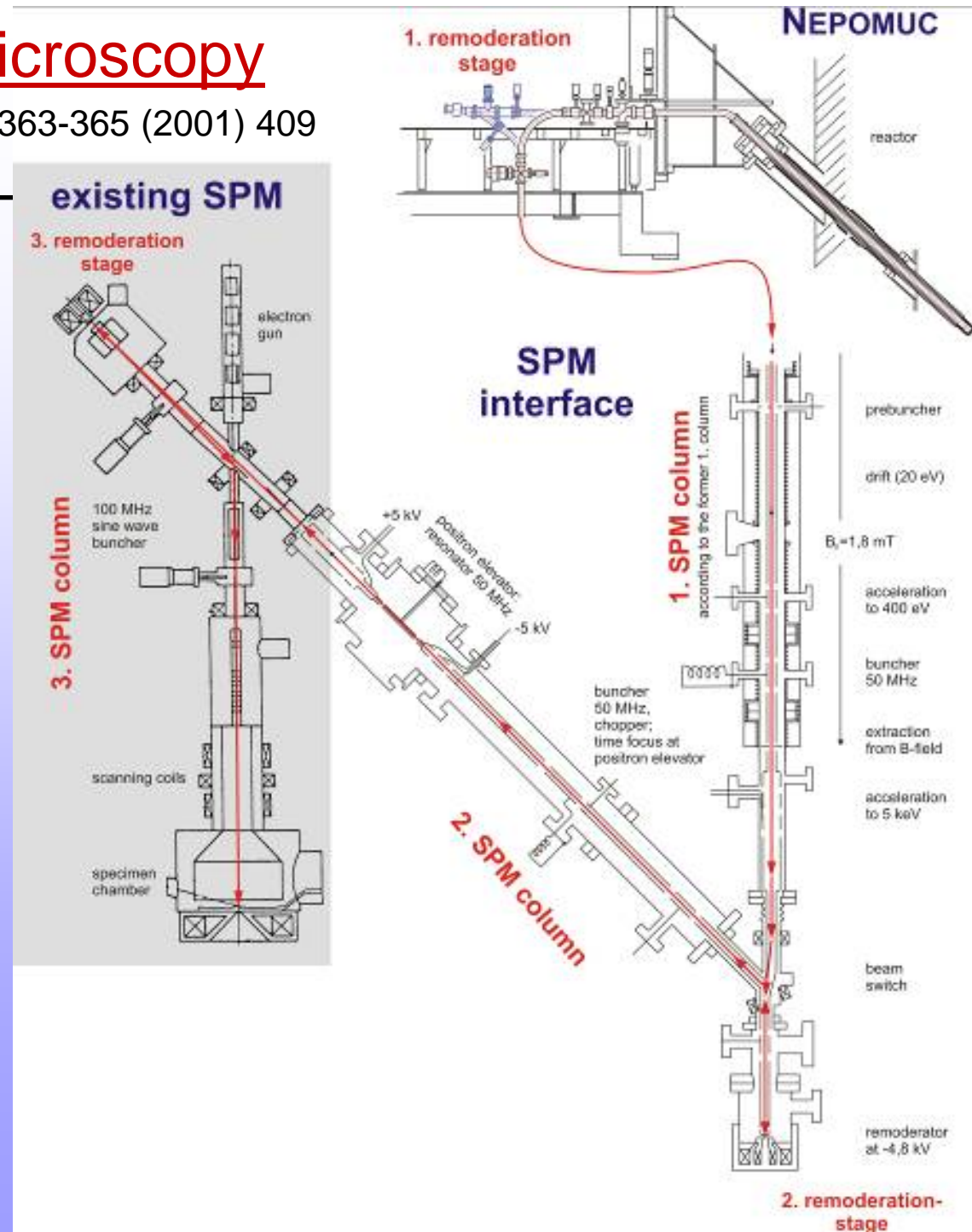


3D positron microscopy

G. Kögel, Mat. Sci. For. 363-365 (2001) 409

- up to $10^6 e^+$ / second
 - in 100 nm beam spot
 - 50 MHz bunches
 - $dt \sim 100$ ps
- => less than 1 e^+ per bunch
- But about 10 to 1000 defects in the beam spot

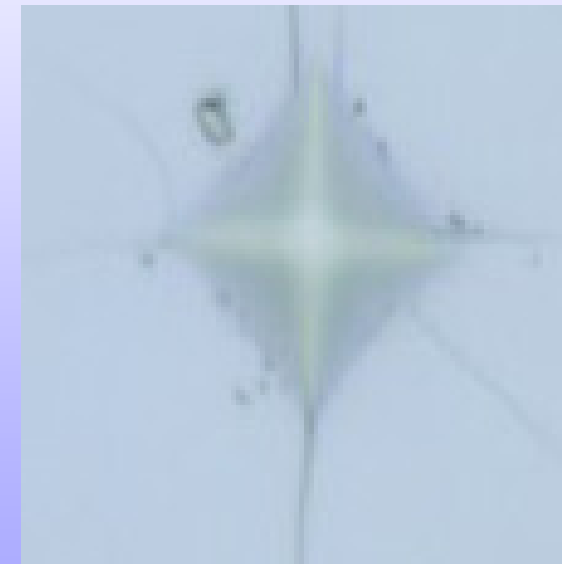
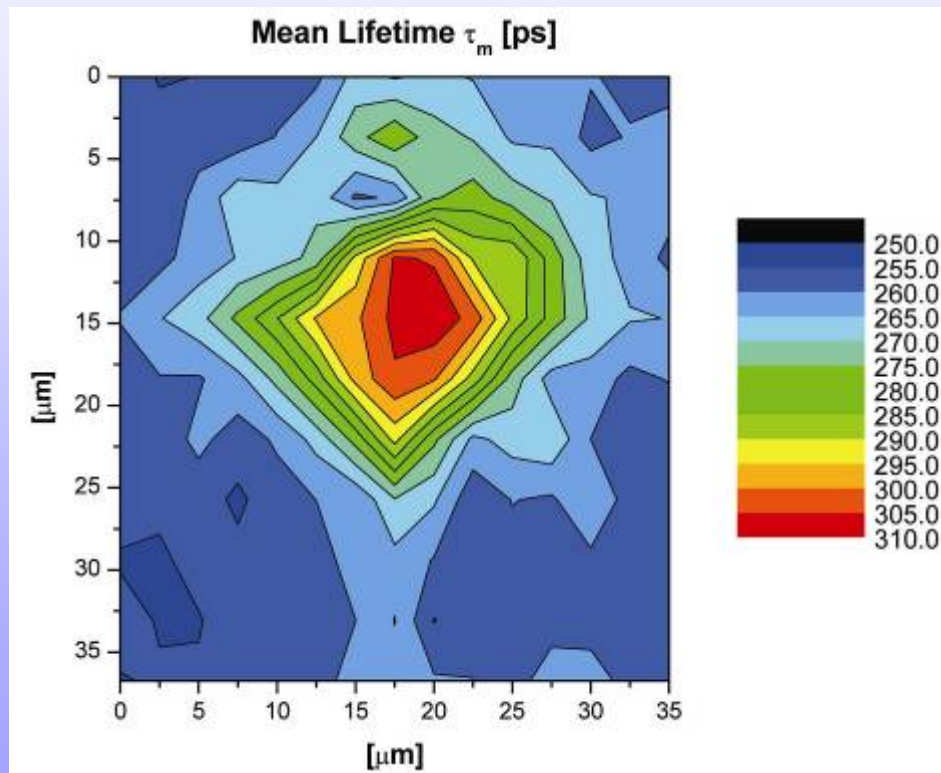
Günther Dollinger



SPM: lateral resolution

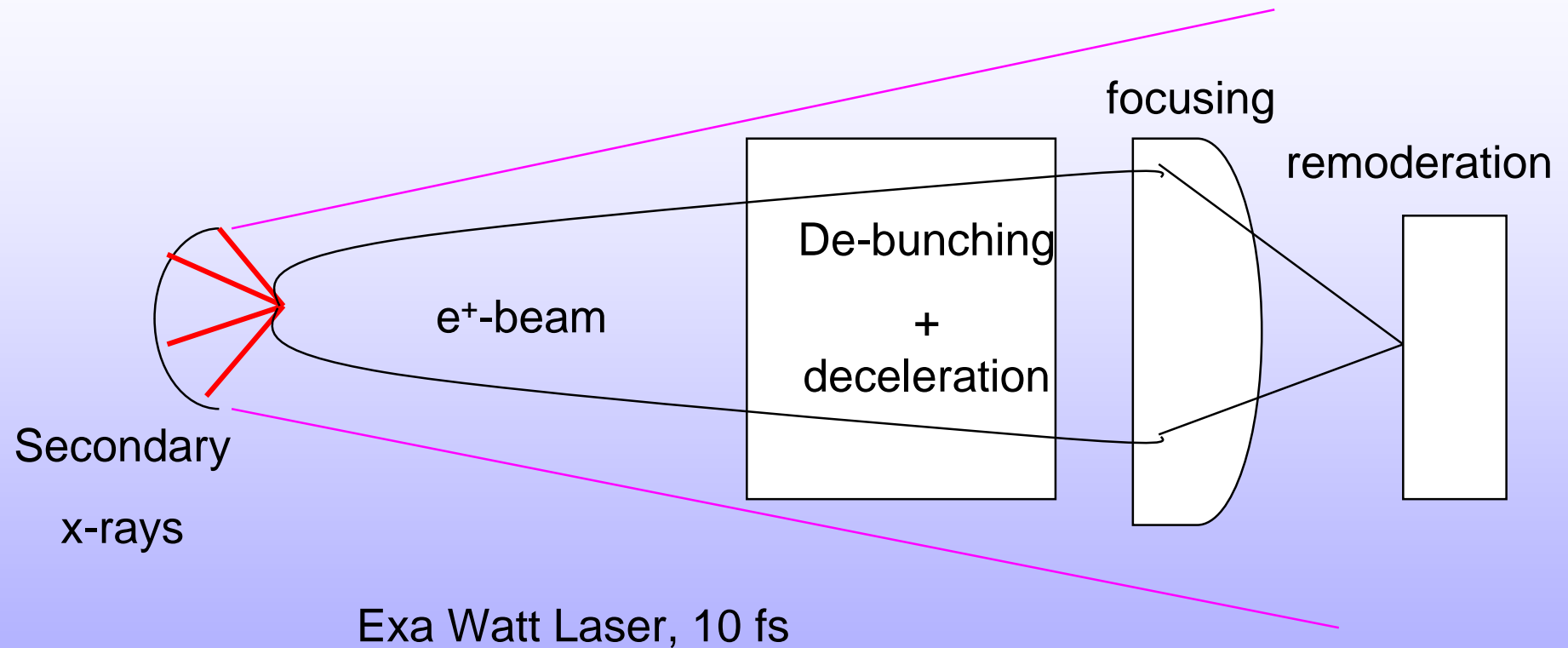
Indentation in GaAs:

- beam energy 16 keV; mean implantation depth 550 nm; resolution 2 μm ; step-size 2.5 μm ;
- two lifetimes in the centre: 70% with 365 ps \Rightarrow **vacancy clusters**



Optical image

Positrons from Laser driven source



=> $10^4 - 10^{10} e^+$ per bunch !

New physics with positron bunches in matter

Do everything as with other sources
plus

Interaction of positrons with matter

1) Quantitative determination of defect densities:

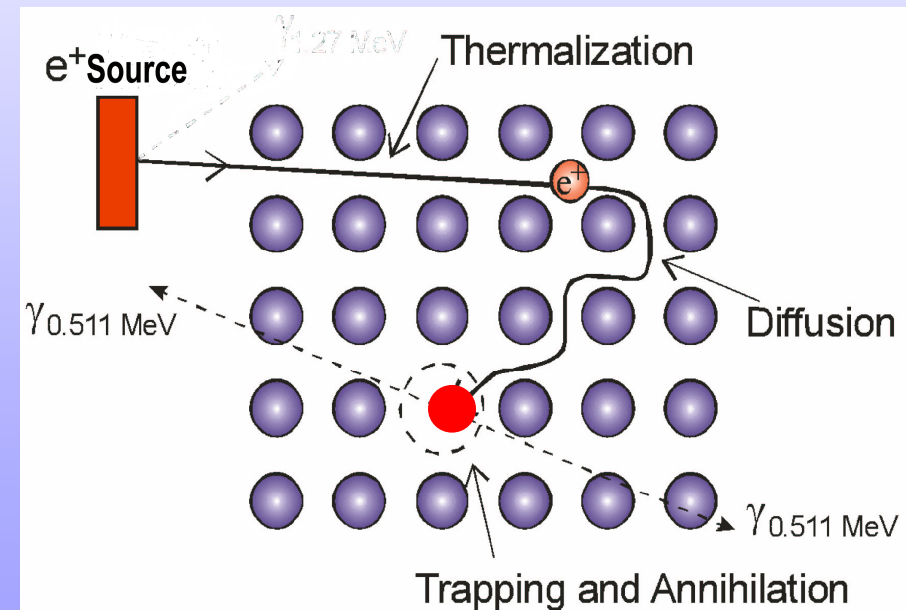
Structural materials => defect density
 $10^{18}/\text{cm}^3 - 10^{20}/\text{cm}^3$

=> $10^3 - 10^5$ defects in a cube of
 $100 \times 100 \times 100 \text{ nm}^3$

If more e^+ per bunch than defects in the spot

=> All defects are filled => change of lifetime spectrum at a certain number of positrons

=> Quantitative measure of defect density !



Bose Einstein condensate of positronium in small cavities

e^+e^- are bosons

Interaction of those bosons in the cavity
Above critical density given by

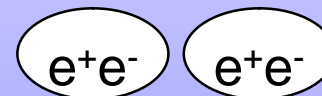
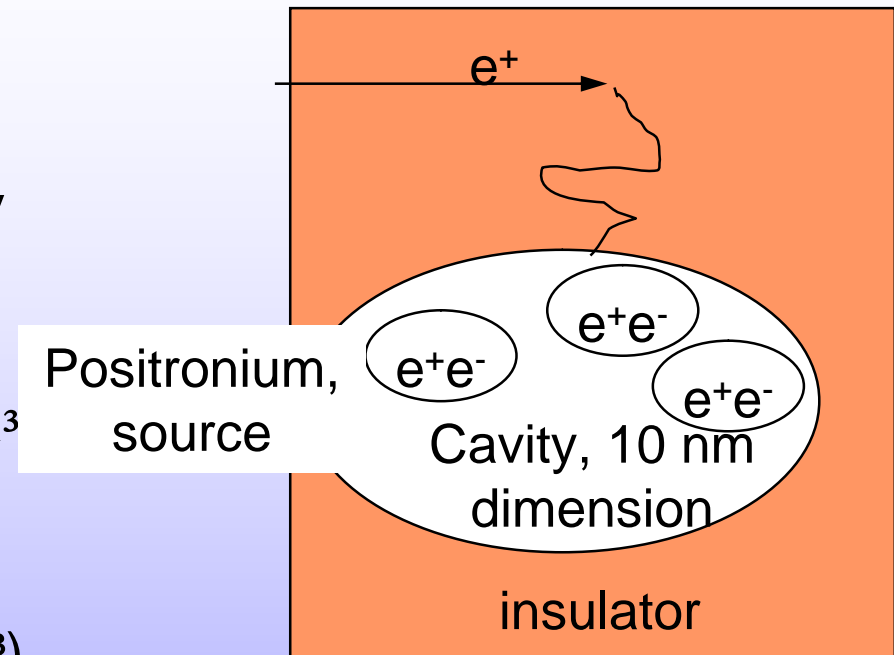
$$\frac{N_{e^+e^-}}{V} = \frac{1.306}{4} \left(\frac{2Mc^2kT}{\pi\hbar c^2} \right)^{3/2} = 8.2 \cdot 10^{-2} / nm^3$$

More than 100 positroniums (same spin alignment) in cavity (1000 nm^3)

⇒ **Bose-Einstein condensate at room temperature**

⇒ 10^{10} in cavity, $1 \mu\text{m}$ diameter 1cm length ⇒ **511 keV x-ray laser possible**

(Mills et al. Mat. Sci. For. 445-446 (2004)424



Molecule generation, signature:
4.941 eV excitation energy

J. Usukura et. al. Phys. Rev. A 58 (1998)
1918



Conclusion

Questions to solve in future:

Is laser driven particle source competitable to standard sources

Replace accelerators, reactors . . .

Intensities? Brilliances?

i.e. bunched positron beams from reactor source plus e^+ -traps?

If competitable to other sources:

than a lot of applications in materials science

Muons

μ^+ as a light version of the proton => diffusion studies

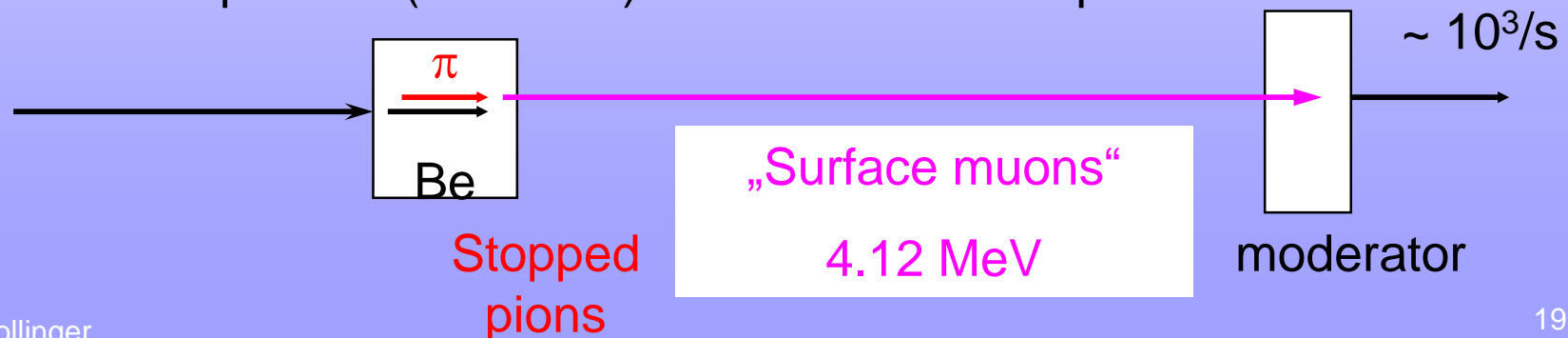
Polarised μ^+ : decay assymetry tells about spin direction at decay time

=> spin rotation in magnetic field

=> local magnetic probé

Generation of μ^+ from π^+ -beams or stopped π^+ :

e.g. at PSI: 2 mA protons (800 MeV) => $\sim 10^6 - 10^9 \mu^+ / s$



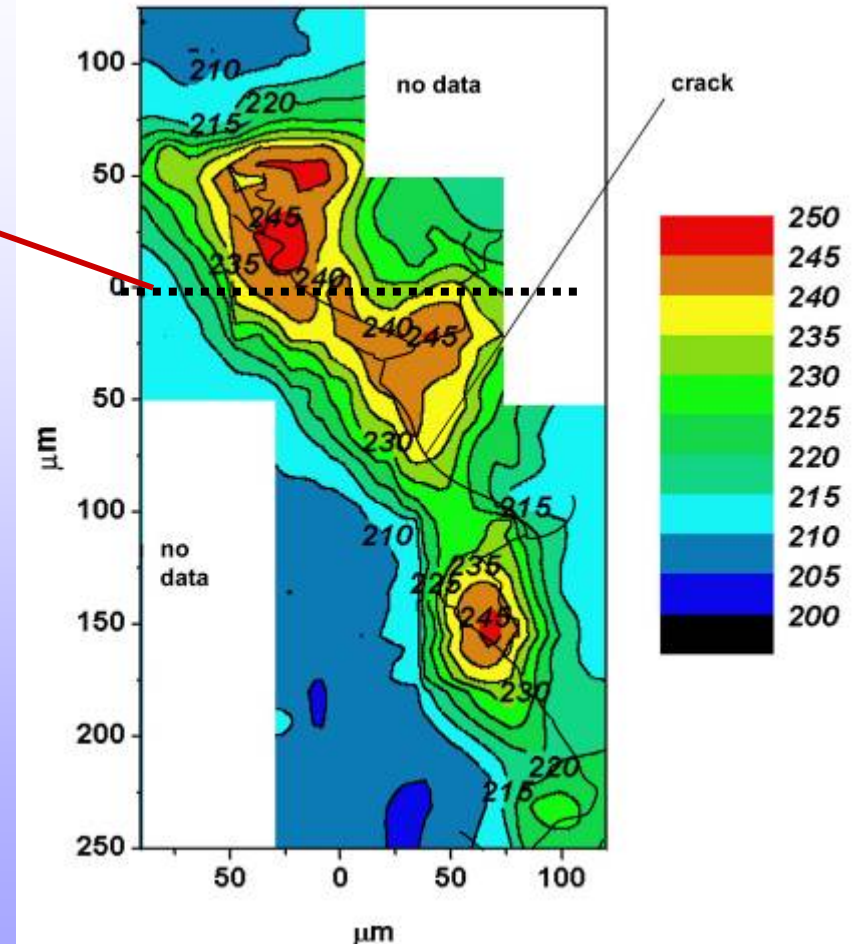
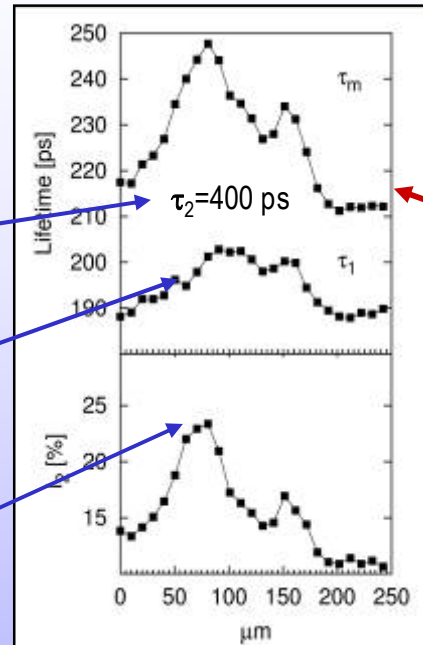
SPM: Lebensdauerbild eines Ermüdungsrisses in Cu

Linescan:
9000 s / Pixel

Leerstellen-
cluster

Versetzungen

Einfangrate
Leerstellencluster
1 / 3 Einfangrate
an Versetzungen



- Strahlenergie: 16 keV
- Auflösung: 5 μm
- **Gesamte Messdauer: 200 h !**
- Hauptergebnis:
Versetzungen (τ_1) und
grosse Leerstellencluster (τ_2)

W. Egger, G. Kögel, P. Sperr, W. Triftshäuser,
J. Bär, S. Rödling, H.-J. Gudladt
Applied Surface Science 194 (2002) 214-217

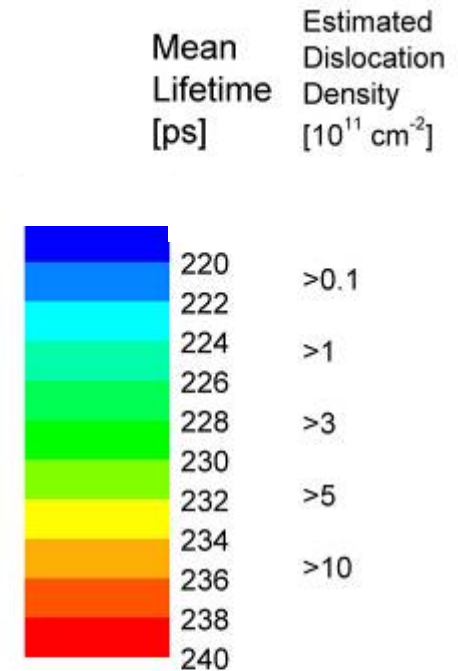
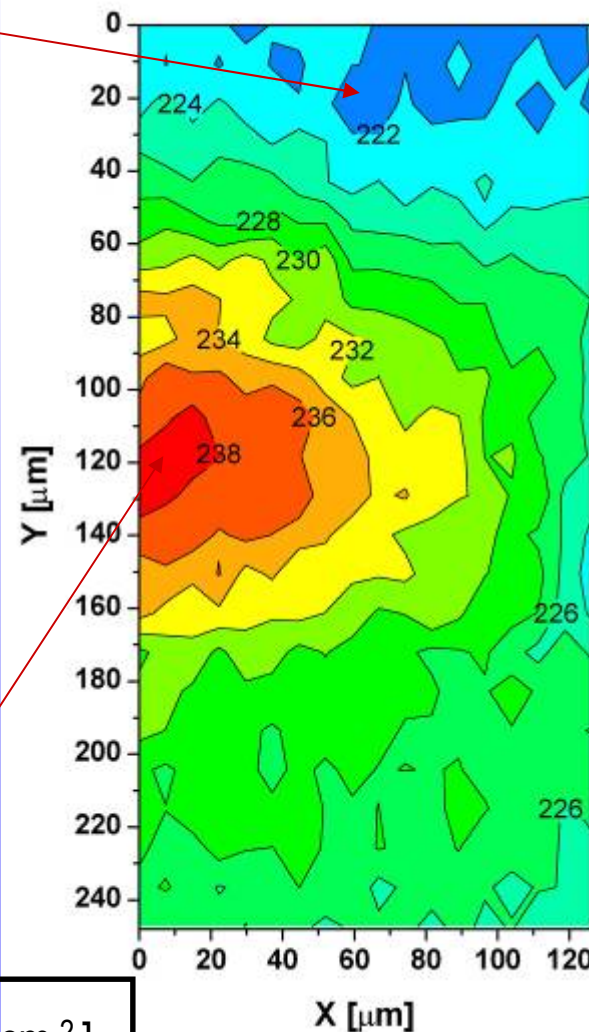
SPM: Lebensdauerbild eines Ermüdungsrisses in Al 6013

- Strahlenergie 12 keV, Auflösung 5µm, Schrittweite 10 µm, $3 \cdot 10^5$ Ereignisse / Pixel

Nur Einfang an Mg / Si-Clustern!



Nur **Versetzungen** in der Umgebung der Rißspitze!

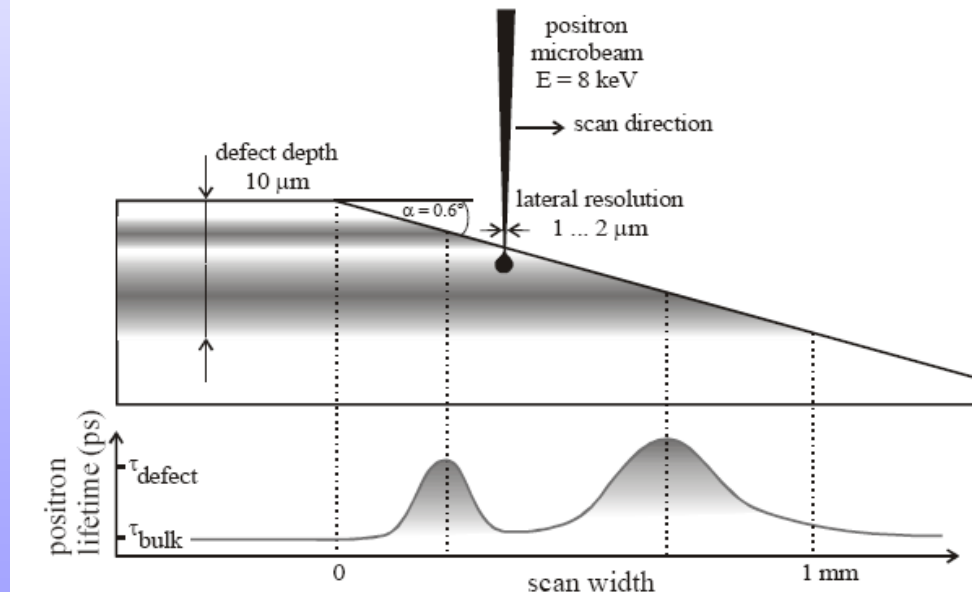


W. Egger, G. Kögel,
P. Sperr, W. Triftshäuser,
J. Bär, S. Rödling, H.-J. Gudladt
Mater. Sci. Eng. (A)
387- 398 (2004) 317

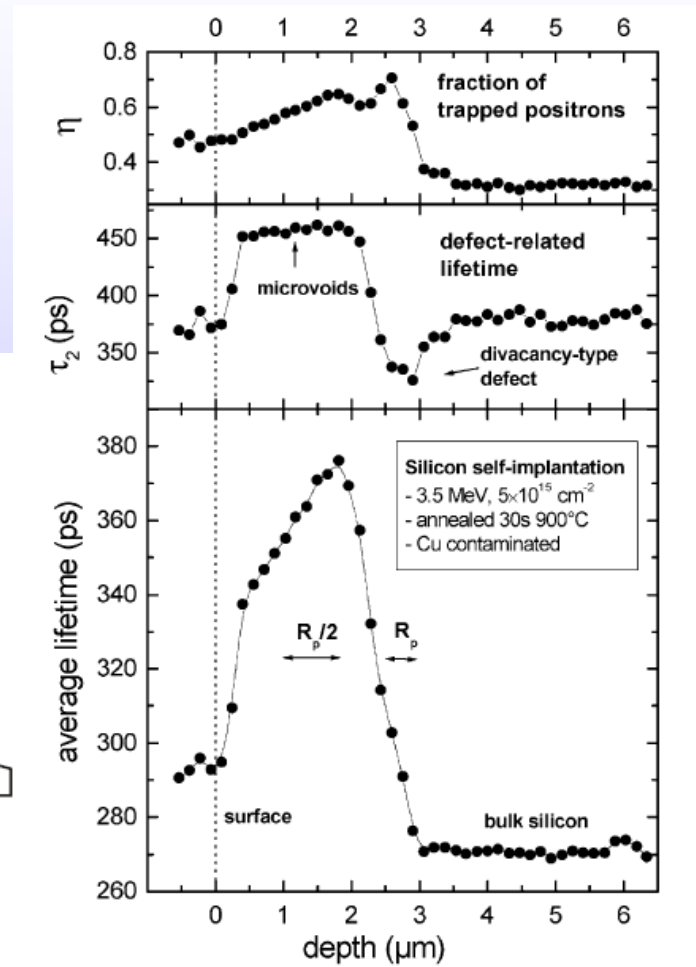
$$C_{\text{disl}} = 4 \cdot 10^{11} (\tau - 220) / (240 - \tau) [\text{cm}^{-2}]$$

SPM: Keilschliffmethode zur Erhöhung der Tiefenauflösung

- Selbstimplantation von Si (3.5 MeV; $5 \times 10^{15} \text{ cm}^{-2}$)
Ausheilung (900° C, 30 s)
- Getterzonen bei R_p und $R_p/2$
- keine Defekte mit TEM bei $R_p/2$ sichtbar
- bei $R_p/2$: Defekte leerstellenartig oder interstitiell?
- **Keilschliff** zieht Getterzonen auf 1 mm auseinander



- Ergebnis SPM-Messung: **Leerstellencluster bei $R_p/2$**



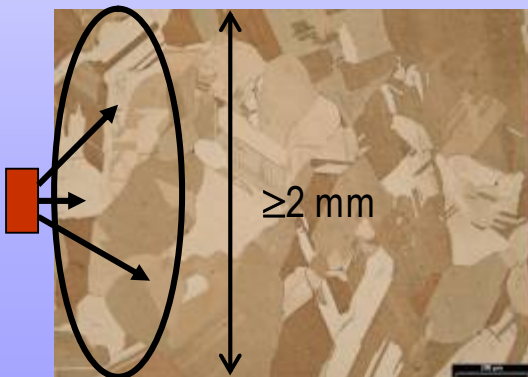
R. Krause-Rehberg, F. Bömer, F. Redmann,
W. Egger, G. Kögel, P. Sperr, W. Triftshäuser
Physica B, 308-310 (2001), 442-445

Monoenergetische Positronenstrahlen

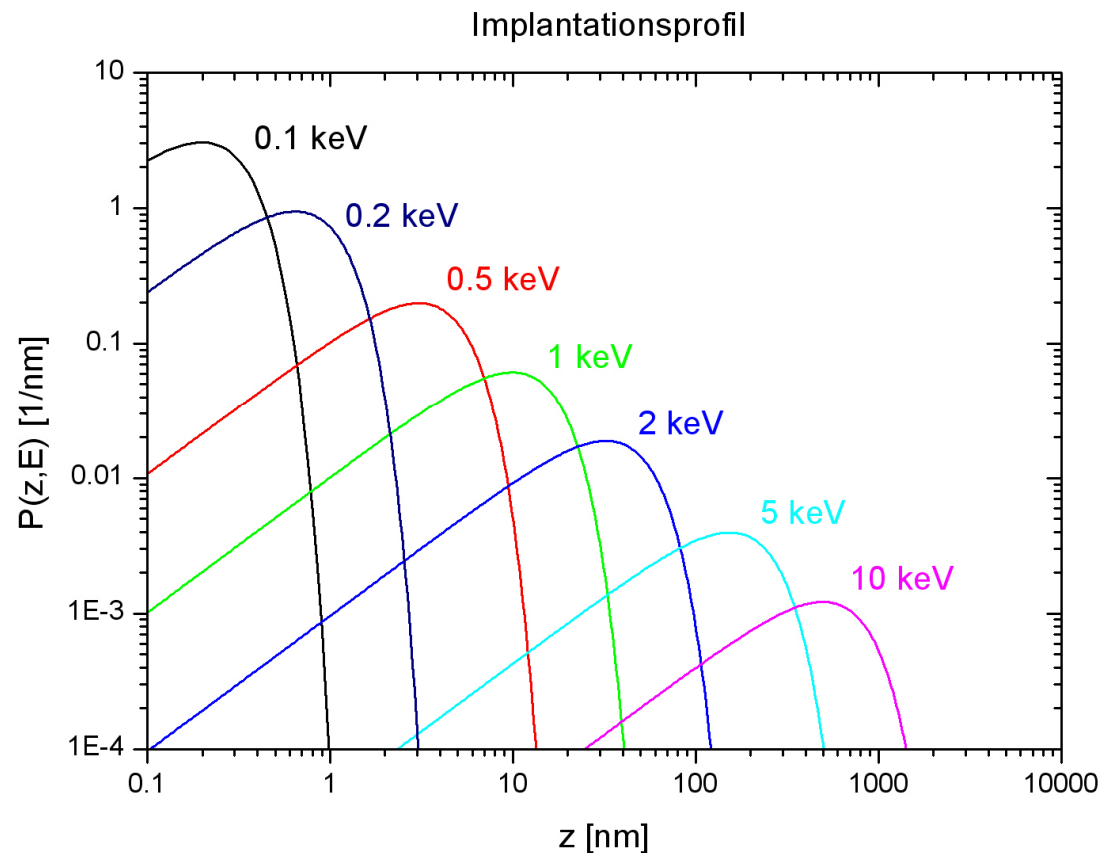
- Konventionelle Methode: Defektstruktur über mm^3 gemittelt.
- Problem: Grenzflächen, Oberflächen, Ausscheidungen etc. durch Volumensignal überdeckt
- Lösung: Monoenergetische Positronenstrahlen mit variabler Energie

Konventionell

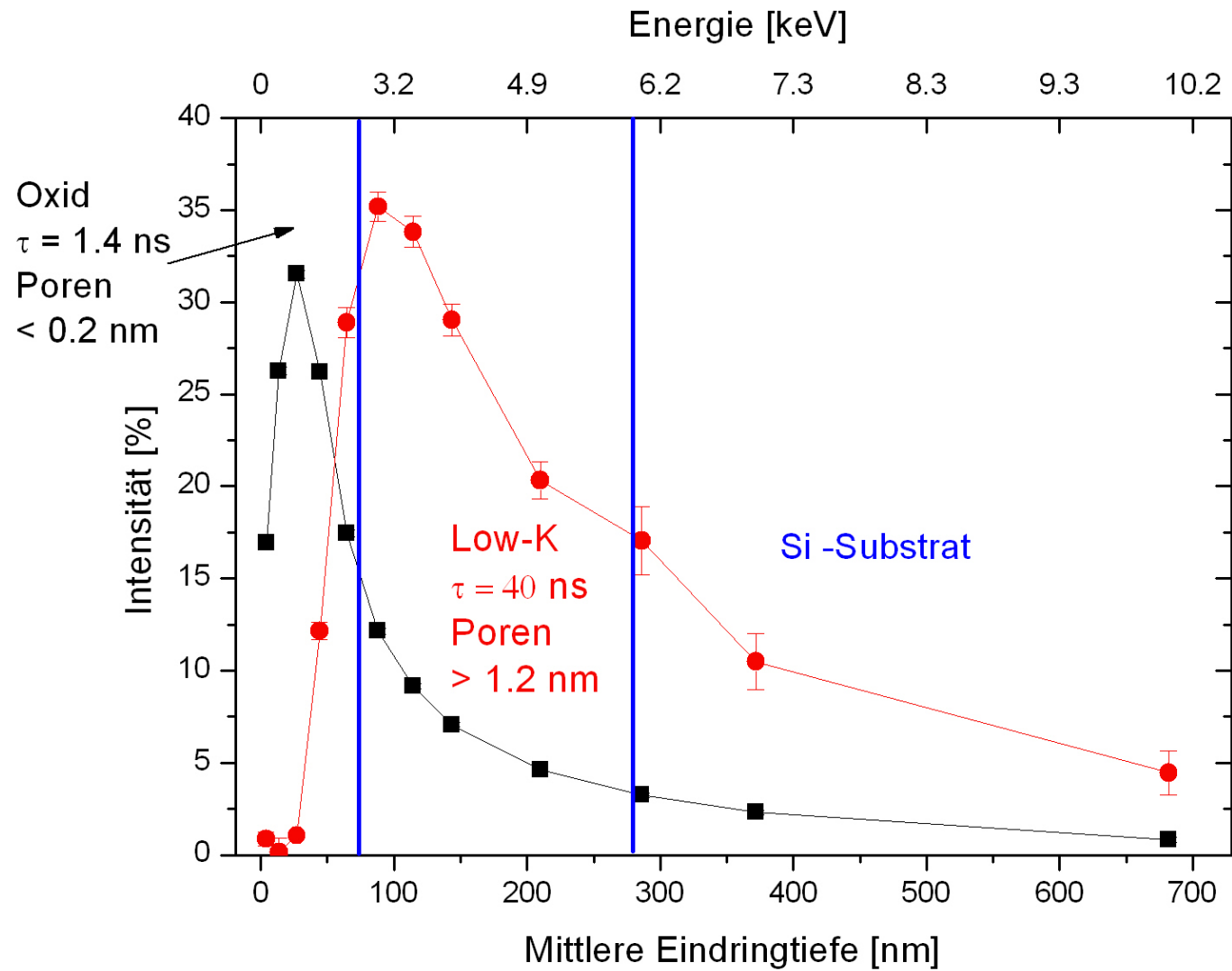
Positronen ($E \leq 600 \text{ keV}$)



Günther Dollinger



Tiefenprofil





PLEPS: Pulsed Low Energy Positron System

Quelle: < 30 mCi
Energie: 0.5-20 keV
Pulsung: 50 MHz
Zeitfenster: 20 ns

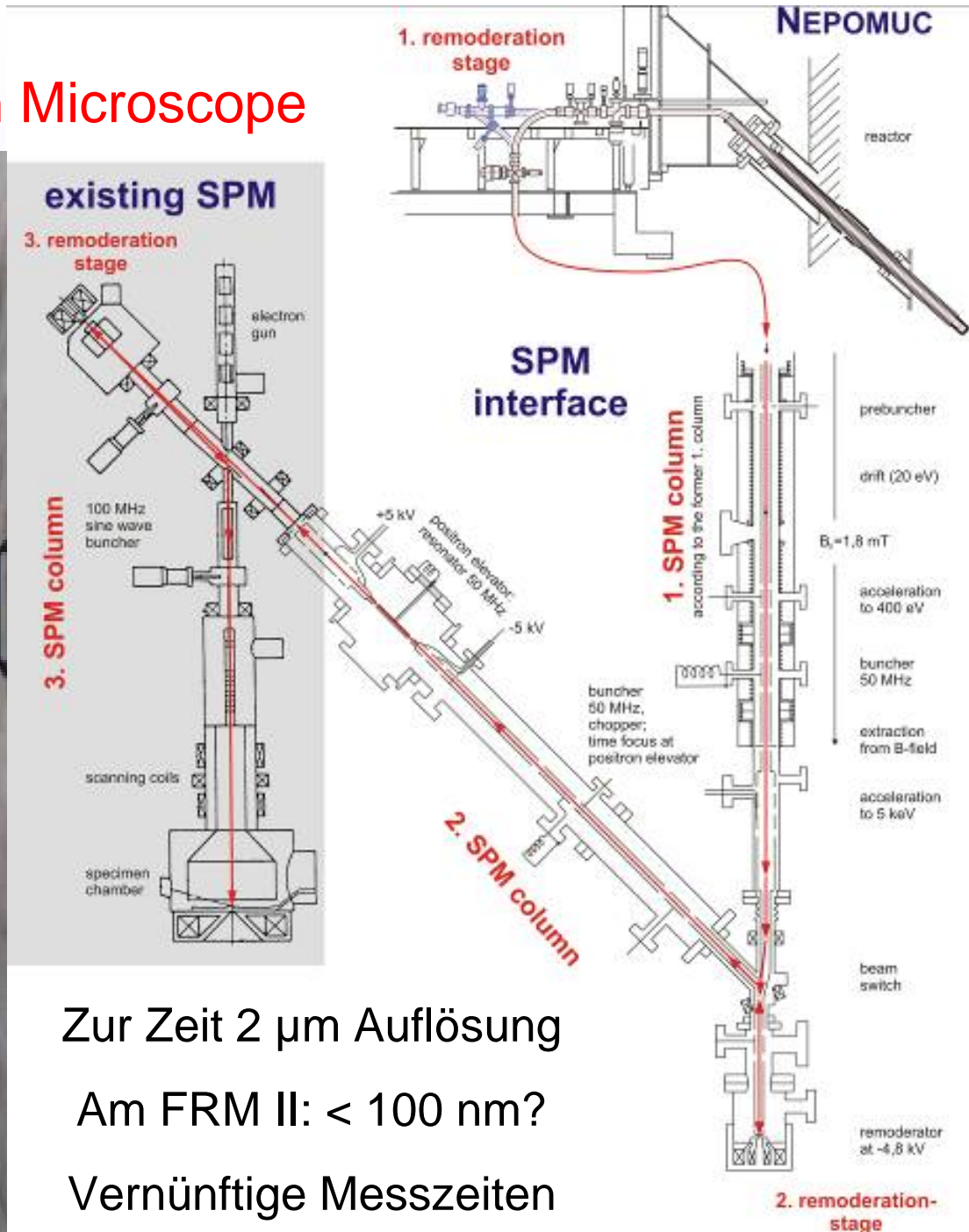
Zählrate: 500 / s
Pulsbreite: 240 ps
Peak/BG: 10^4
Beamspot: 2-3 mm

Dauer einer Meßreihe
(0.5-20 keV): 1d





SPM: Scanning Positron Microscope



Zur Zeit 2 μm Auflösung

Am FRM II: < 100 nm?

Vernünftige Messzeiten



Ziele

Etablierung der Positronenannihilation zur Untersuchung ultradünner Schichten und Grenzflächen:

Sind Monolagen-Schichten im Defekt-Tiefenprofil sichtbar?
Charakterisierung der Defekte, Defektdichte

Elektrische / Optische Beeinflussung der Positronen im Festkörper

Neuer Zugang zur Untersuchung elektronischer Eigenschaften:

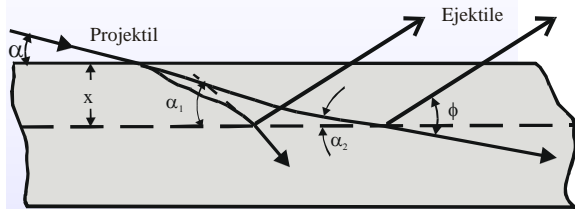
z. B. Untersuchung der Defektdichte an Oxid-Halbleitergrenzfläche eines Feldeffekt- oder Tunneltransistors

Anwendung auf Materialien im Verbund



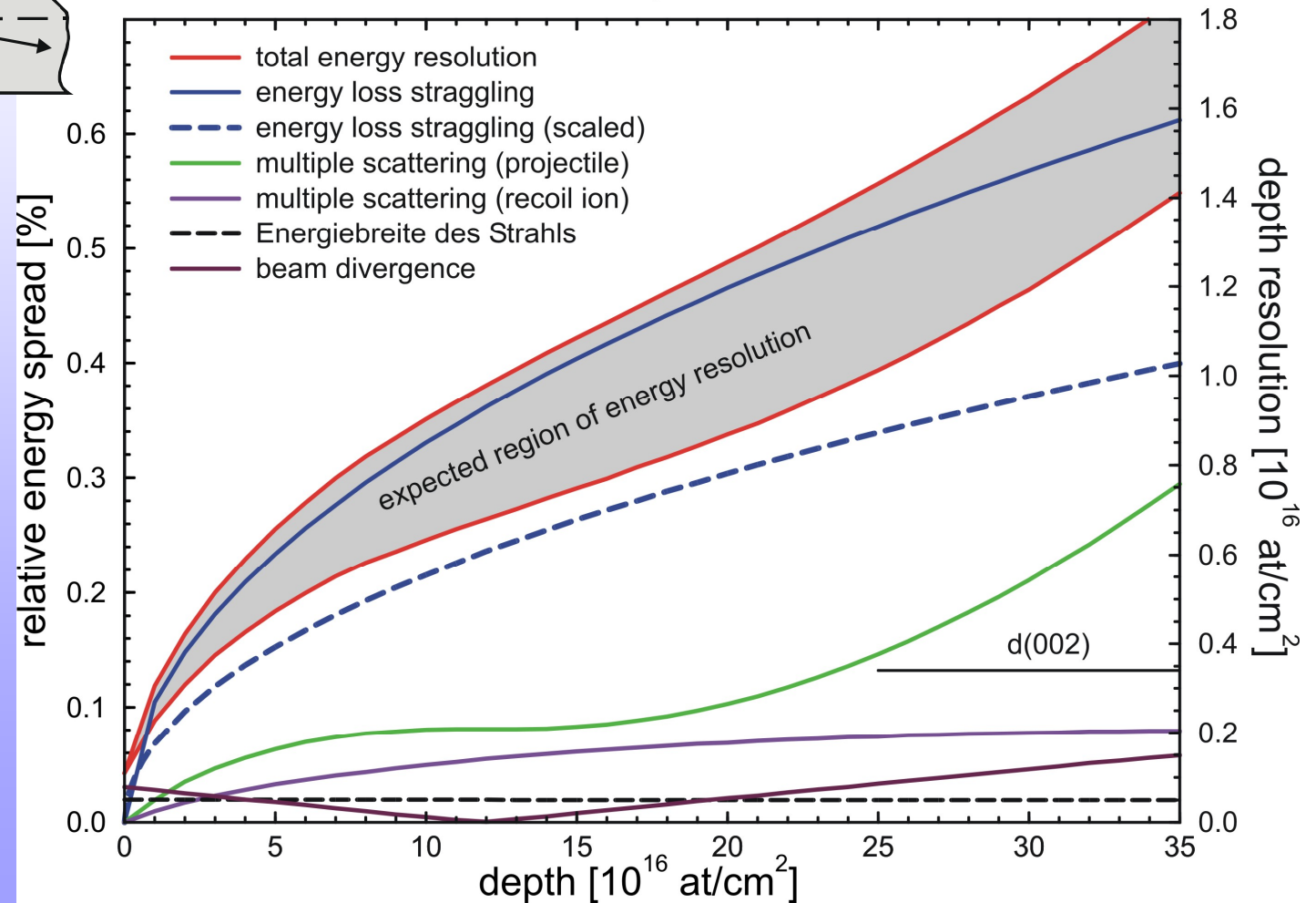
Depth resolution

Depth code, E. Szilagy



60 MeV ^{127}I \rightarrow carbon

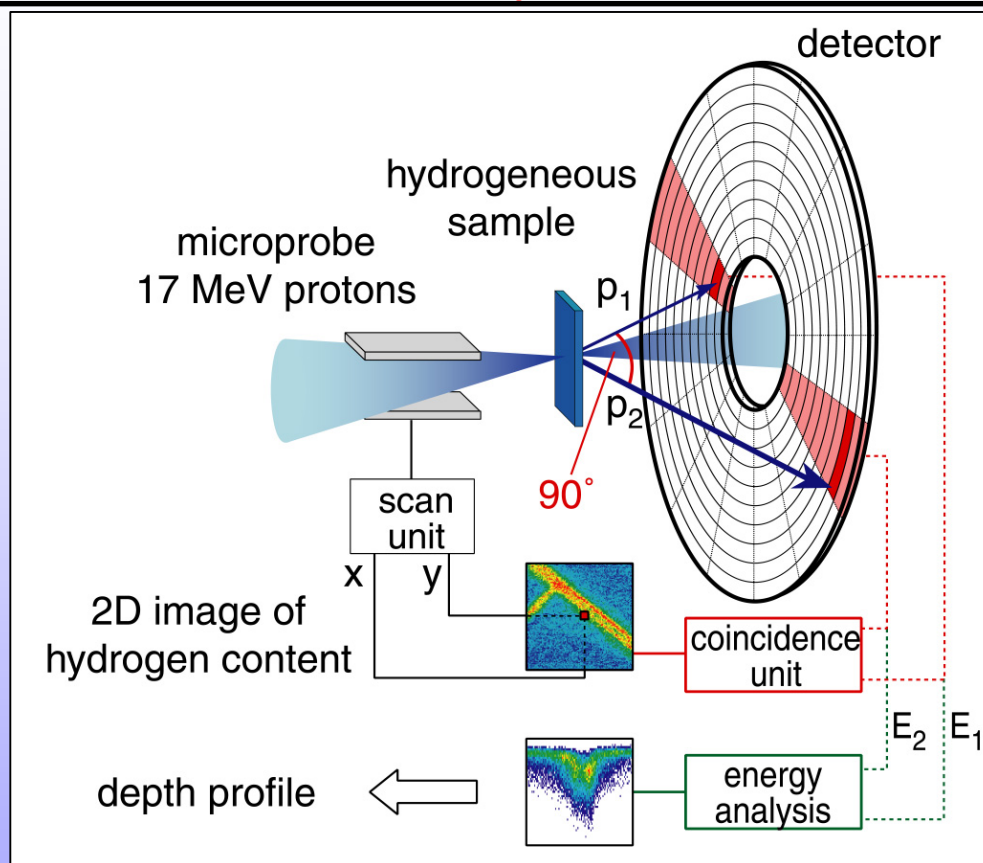
$a = 4.7^\circ$, $f = 10^\circ$





Ion	Target	Experiment [keV/at/cm ²]	Tables (Ziegler) [keV/at/cm ²]	Relativer Abstand
40 MeV 197Au	C	7,63E-16	7,40E-16	3,08%
40 MeV 197Au	O	8,14E-16	8,51E-16	-4,50%
40 MeV 197Au	Al	9,49E-16	1,12E-15	-18,12%
40 MeV 197Au	Si	1,29E-15	1,24E-15	4,10%
40 MeV 197Au	Hf	2,25E-15	2,41E-15	-7,16%

3D Hydrogen Microscopy by Proton-Proton Scattering



coincident detection

sensitivity < 1 at-ppm

spatial resolution

microprobe

lateral < 1 μm

strip detector

depth < 5 μm

sample preparation

17 MeV protons

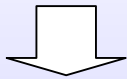
sample thickness 50 μm

**Only method for "3D hydrogen microscopy" with ppm-sensitivity
quantitative & matrix independent**

Hydrogen in CVD-diamond

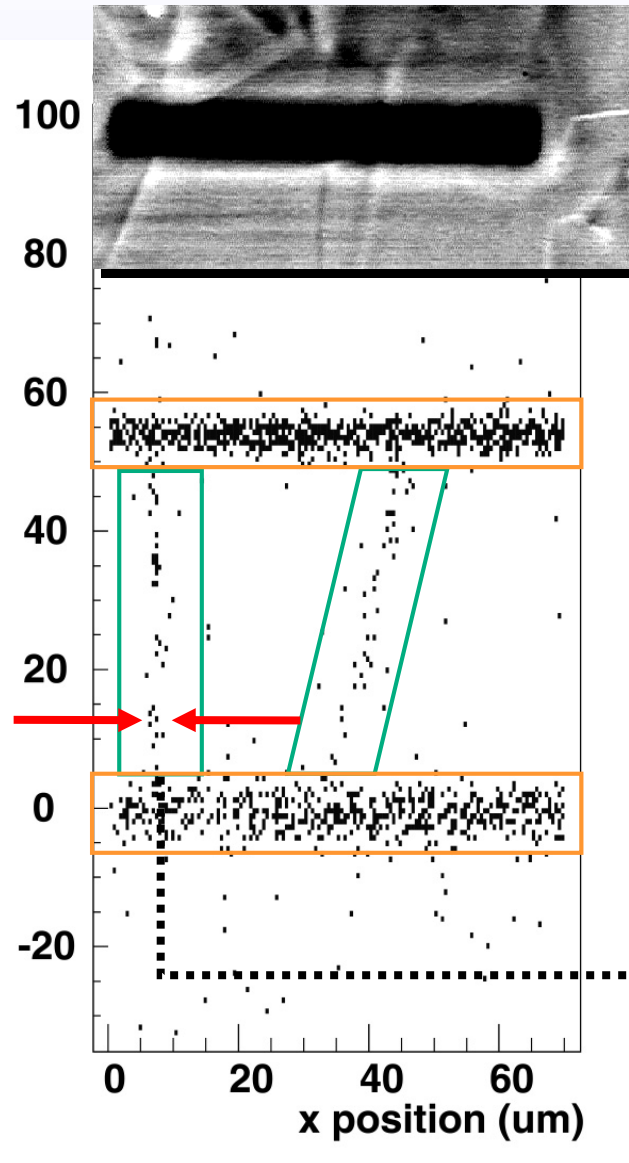
P. Reichart et al. Science, 306 (2004) 1637

hydrogen on surface

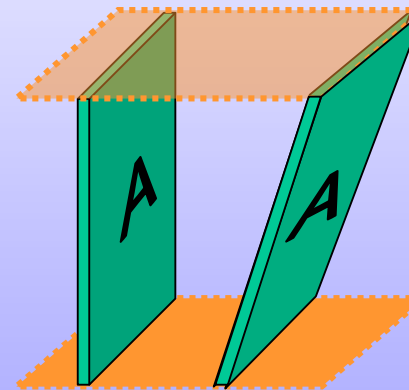


$4.3 \cdot 10^{15} \text{ at/cm}^2$

$2.7 \cdot 10^{15} \text{ at/cm}^2$



hydrogen on grain boundary



projected to face A

$3.0 \cdot 10^{14} \text{ at/cm}^2$

$2.9 \cdot 10^{14} \text{ at/cm}^2$

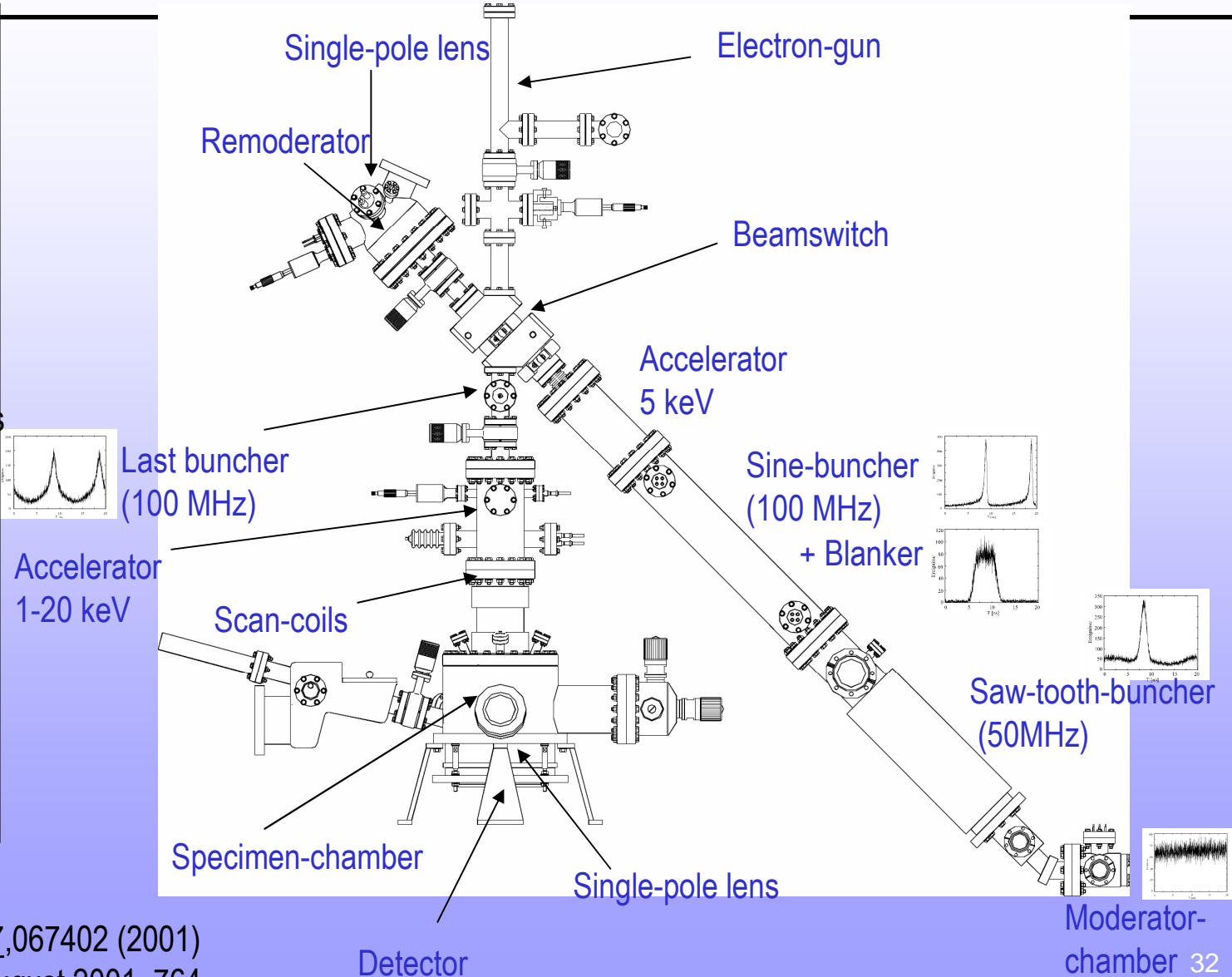
lateral FWHM 0.5 μm

content inside grain
< 0.08 at-ppm



Scanning Positron Microscope (SPM)

source:	< 30 mCi
energy:	1-20 keV
pulsing:	50 MHz
time-window:	20 ns
count-rate:	500 / s
timeresolution:	250 ps
peak / BG:	10^3
beam-spot:	$\geq 2 \mu\text{m}$
recording-time	
XY scan:	
week(s) !	



Phys.Rev.Lett. 87,067402 (2001)

Günter Delling, Nature 412, 23 August 2001, 764